4/17/2013

RELIABILITY MONITOR REPORT
FOR

MFN 0.18µm Silicon Gate CMOS (S18)

MAXIM INTEGRATED

160 RIO ROBLES
SAN JOSE, CA 95134

This Report was prepared by
MAXIM INTEGRATED Reliability Engineering

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX8959EWG+	MAX98400AET

The calculated failure rate for devices using this process is:

FAILURE RATE: MTTF (YRS): 7181 QUANTITY: 198 FAILS: 0 FITS: 15.9

The parameters used to calculate this failure rate are as follows:

Cf: 60% Ea: 0.7 Tu: 25 °C

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 4/1/2012 and 3/31/2013 .

Process Information:

Process Description: MFN 0.18µm Silicon Gate CMOS (S18)

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT		QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	1303	MAX8959EWG+T	135°C	192	HRS	48	0	JAJI8Z003A#
HIGH TEMP OP LIFE	1304	MAX98400AETX+	135°C	192	HRS	150	0	JAJC7Z003S#
					Total:		**0**	

TEMPERATURE CYCLE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT		QUANTITY	FAILS	LOT NO.
TEMP CYCLE, 5' RAMP, 10' DWELL	1304	MAX98400AETX+	-65C TO 150C	500	CYS	80	0	JAJC7Z003S#
					Total:		**0**	

TEMPERATURE HUMIDITY BIAS

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT		QUANTITY	FAILS	LOT NO.
BIASED MOISTURE	1304	MAX98400AETX+	130C, 85% R.H.	100	HRS	80	0	JAJC7Z003S#
					Total:		**0**	

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